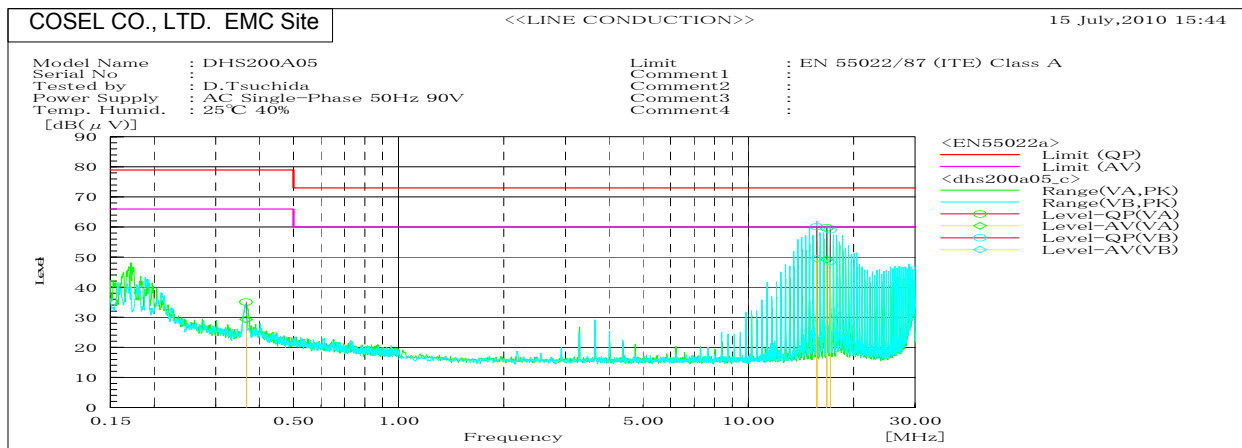
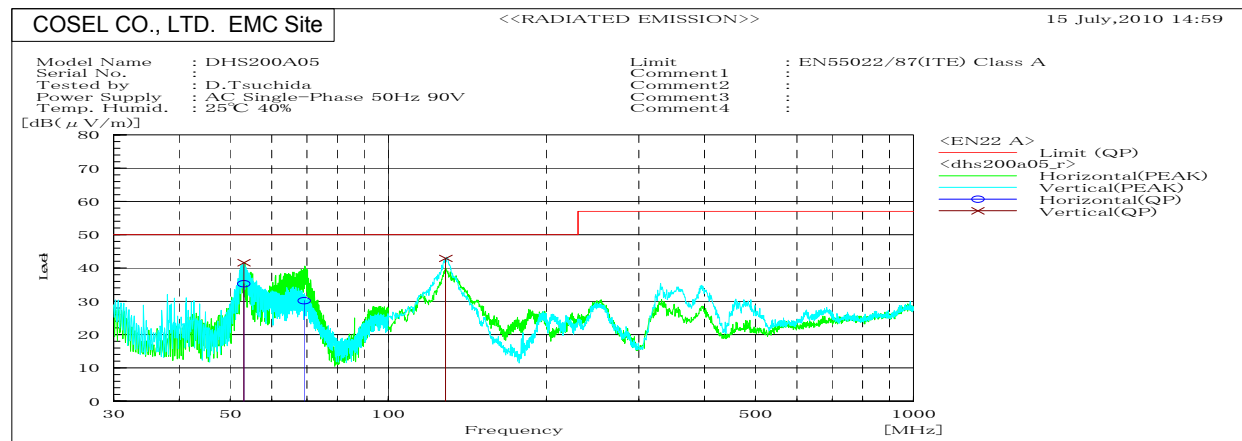


DATA SHEET		Date	10-Aug-10
Model	DHS200A05	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida



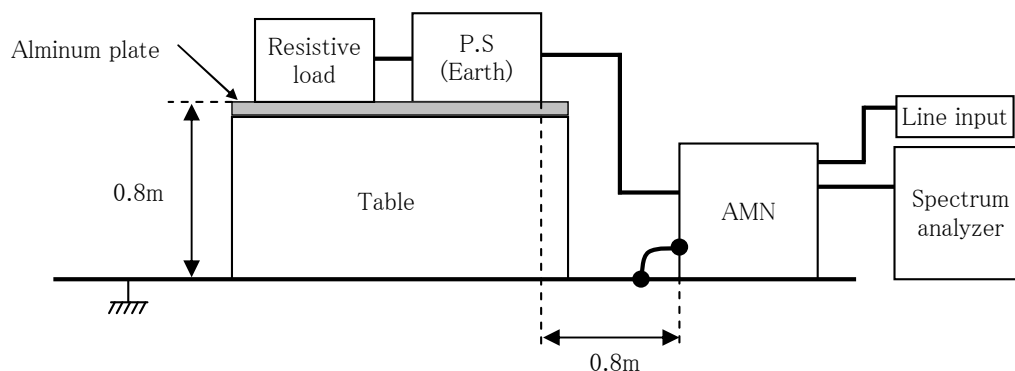
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.36602		VA	25	19.2	10.1	35.1	29.3	79	66	43.9	36.7	Pass	
15.6762		VB	49.2	38.7	10.9	60.1	49.6	73	60	12.9	10.4	Pass	
16.7653		VA	49	38.4	10.8	59.8	49.2	73	60	13.2	10.8	Pass	
17.1336		VB	48.1	37.4	11	59.1	48.4	73	60	13.9	11.6	Pass	



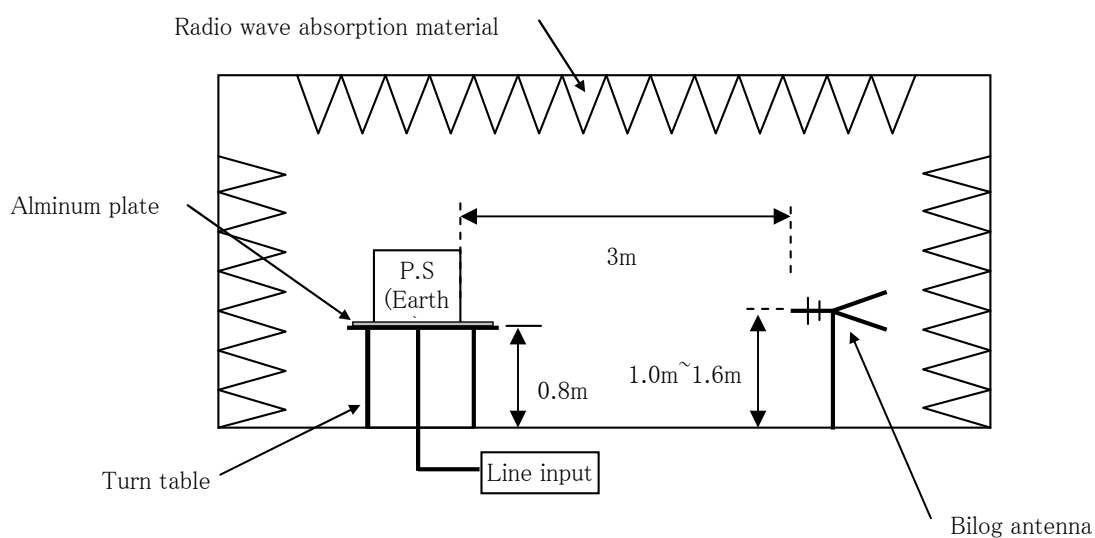
Frequency MHz	Polarization	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
53.141	V	Stable	66.6	-25	41.6	50	8.4	Pass	132	105	
53.076	H	Stable	60.3	-25	35.3	50	14.7	Pass	157	183	
69.137	H	Stable	55.6	-25.4	30.2	50	19.8	Pass	148	174	
128.688	V	Stable	62.5	-19.6	42.9	50	7.1	Pass	130	55	

DATA SHEET		Date	10-Aug-10
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida

## 1. Line conduction



## 2. Radiated emission

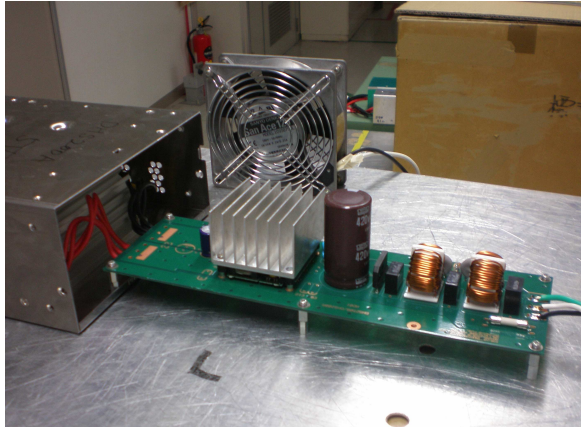


Test: EMI

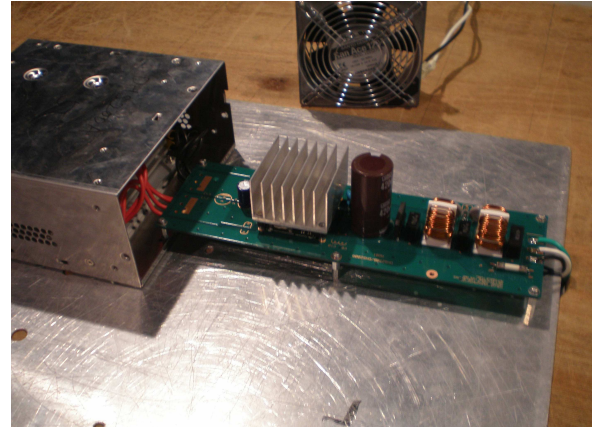
Model Name:DHS200A Series

○ Photographs of Test Set-Up

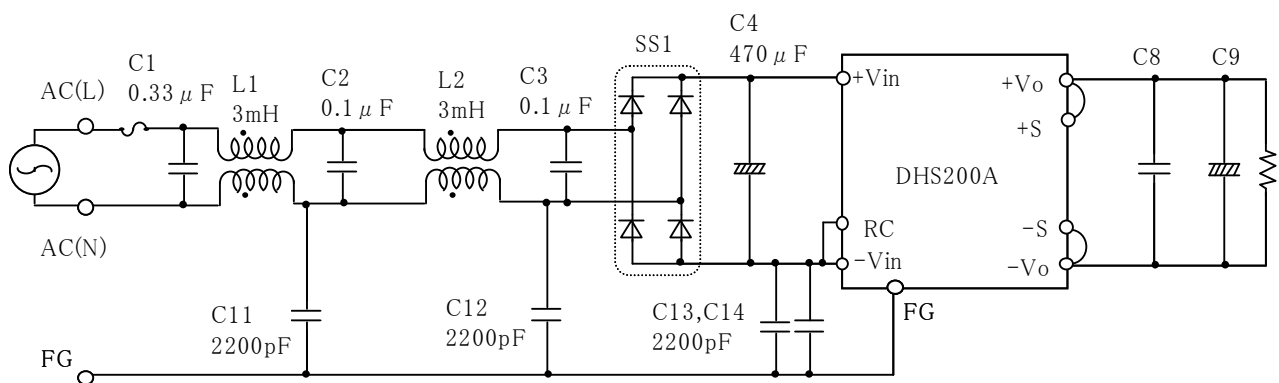
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



L1,L2 : SC-10-300(NEC TOKIN)

SS1 : D10XB60(SINDENGEN)

C8 : DHS200A05	10 $\mu$ F	C9 : DHS200A05	2200 $\mu$ F
DHS200A12	10 $\mu$ F	DHS200A12	1000 $\mu$ F
DHS200A15	10 $\mu$ F	DHS200A15	1000 $\mu$ F
DHS200A24	4.7 $\mu$ F	DHS200A24	470 $\mu$ F